

### ADC12L030/ADC12L032/ADC12L034/ADC12L038 3.3V Self-Calibrating 12-Bit Plus Sign Serial I/O A/D Converters with MUX and Sample/Hold

### **General Description**

The ADC12L030 family is 12-bit plus sign successive approximation A/D converters with serial I/O and configurable input multiplexers. These devices are fully tested with a single 3.3V power supply. The ADC12L032, ADC12L034 and ADC12L038 have 2, 4 and 8 channel multiplexers, respectively. Differential multiplexer outputs and A/D inputs are available on the MUXOUT1, MUXOUT2, A/DIN1 and A/DIN2 pins. The ADC12L030 has a two channel multiplexer with the multiplexer outputs and A/D inputs internally connected. On request, these A/Ds go through a self calibration process that adjusts linearity, zero and full-scale errors to less than  $\pm 1/2$  LSB each.

The analog inputs can be configured to operate in various combinations of single-ended, differential, or pseudo-differential modes. A fully differential unipolar analog input range (0V to +3.3V) can be accommodated with a single +3.3V supply. In the differential modes, valid outputs are obtained even when the negative inputs are greater than the positive because of the 12-bit plus sign two's compliment output data format.

The serial I/O is configured to comply with NSC's MICROWIRE™ and Motorola's SPI standards. For voltage references, see the LM4040 or LM4041 data sheets.

### **Features**

- 0V to 3.3V analog input range with single 3.3V power supply
- Serial I/O ( MICROWIRE and SPI Compatible)
- 2, 4, or 8 channel differential or single-ended multiplexer
- Analog input sample/hold function
- Power down mode
- Variable resolution and conversion rate
- Programmable acquisition time
- Variable digital output word length and format
- No zero or full scale adjustment required
- Fully tested and guaranteed with a 2.5V reference
- No Missing Codes over temperature

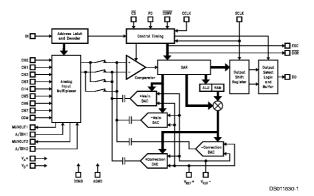
### **Key Specifications**

■ Resolution	12-bit plus sign
■ 12-bit plus sign conversion time	8.8 µs (min)
■ 12-bit plus sign sampling rate	73 kHz (max)
<ul><li>Integral linearity error</li></ul>	±1 LSB (max)
■ Single supply	3.3V ±10%
■ Power dissipation	15 mW (max)
■ Power down	40 μW (typ)

### **Applications**

- Portable Medical instruments
- Portable computing
- Portable Test equipment

### ADC12L038 Simplified Block Diagram



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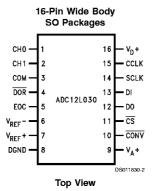
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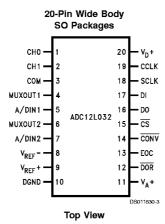
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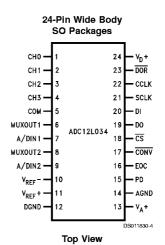
### **Ordering Information**

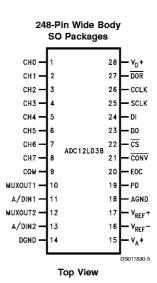
Industrial Temperature Range	NS Package
-40°C ≤ T <sub>A</sub> ≤ +85°C	Number
ADC12L030CIWM	M16B
ADC12L032CIWM	M20B
ADC12L034CIWM	M24B
ADC12L038CIWM	M28B

### **Connection Diagrams**









### **Pin Descriptions**

DΙ

DO

EOC

CS

CCLK The clock applied to this input controls the sucessive approximation conversion time interval and the acquisition time. The rise and fall times of the clock edges should not exceed 1 µs.

**SCLK** This is the serial data clock input. The clock applied to this input controls the rate at which the serial data exchange occurs. The rising edge loads the information on the DI pin into the multiplexer address and mode select shift register. This address controls which channel of the analog input multiplexer (MUX) is selected and the mode of operation for the A/D. With  $\overline{\text{CS}}$  low the falling edge of SCLK shifts the data resulting from the previous ADC conversion out on DO, with the exception of the first bit of data. When  $\overline{CS}$  is low continuously, the first bit of the data is clocked out on the rising edge of EOC (end of conversion). When  $\overline{\text{CS}}$  is toggled the falling edge of CS always clocks out the first bit of data. CS should be brought low when SCLK is low. The rise and fall times

> This is the serial data input pin. The data applied to this pin is shifted by the rising edge of SCLK into the multiplexer address and mode select register. Tables 2, 3, 4, 5 show the assignment of the multiplexer address and the mode select data.

of the clock edges should not exceed 1 µs.

The data output pin. This pin is an active push/pull output when  $\overline{CS}$  is Low. When  $\overline{CS}$  is High this output is in TRI-STATE. The A/D conversion result (D0-D12) and converter status data are clocked out by the falling edge of SCLK on this pin. The word length and format of this result can vary (see Table 1). The word length and format are controlled by the data shifted into the multiplexer address and mode select register (see Table 5).

This pin is an active push/pull output and indicates the status of the ADC12L030/2/4/8. When low, it signals that the A/D is busy with a conversion, auto-calibration, auto-zero or power down cycle. The rising edge of EOC signals the end of one of these cycles.

This is the chip select pin. When a logic low is applied to this pin, the rising edge of SCLK shifts the data on DI into the address register. This low also brings DO out of TRI-STATE. With CS low the falling edge of SCLK shifts the data resulting from the previous ADC conversion out on DO, with the exception of the first bit of data. When CS is low continuously, the first bit of the data is clocked out on the rising edge of EOC (end of conversion). When CS is toggled the falling edge of  $\overline{\text{CS}}$  always clocks out the first bit of data. CS should be brought low when SCLK is low. The falling edge of CS resets a conversion in progress and starts the sequence for a new conversion. When  $\overline{\text{CS}}$  is brought back low during a conversion, that conversion is prematurely ended. The data in the output latches may be corrupted. Therefore, when  $\overline{CS}$  is brought back low during a conversion in progress the data output at that time should be ignored. 
TS may also be left continuously low. In this case it is imperative that the correct number of SCLK pulses be applied to the ADC in order to remain synchronous. After the ADC supply power is applied, it expects to see 13 clock pulses for each I/O sequence. The number of clock pulses the ADC expects is the same as the digital output word length. This word length can be modified by the data shifted in on the DO pin. Table 5 details the data required.

This is the data output ready pin. This pin is an DOR active push/pull output. It is low when the conversion result is being shifted out and goes high to signal that all the data has been shifted

A logic low is required on this pin to program any mode or change the ADC's configuration as listed in the Mode Programming Table (Table 5) such as 12-bit conversion, 8-bit conversion, Auto Cal, Auto Zero etc. When this pin is high the ADC is placed in the read data only mode. While in the read data only mode, bringing CS low and pulsing SCLK will only clock out on DO any data stored in the ADCs output shift register. The data on DI will be neglected. A new conversion will not be started and the ADC will remain in the mode and/or configuration previously programmed. Read data only cannot be performed while a conversion, Auto-Cal or Auto-Zero are in progress.

PD This is the power down pin. When PD is high the A/D is powered down; when PD is low the A/D is powered up. The A/D takes a maximum of 700 µs to power up after the command is aiven.

CH0-CH7 These are the analog inputs of the MUX. A channel input is selected by the address information at the DI pin, which is loaded on the rising edge of SCLK into the address register (see Tables 2, 3, 4).

> The voltage applied to these inputs should not exceed V<sub>A</sub>+ or go below GND. Exceeding this range on an unselected channel will corrupt the reading of a selected channel.

This pin is another analog input pin. It is used as a pseudo ground when the analog multiplexer is single-ended.

MUXOUT1, These multiplexer are the MUXOUT2

> These are the converter input pins. MUXOUT1 is usually tied to A/DIN1. MUXOUT2 is usually tied to A/DIN2. If external circuitry is placed between MUXOUT1 and A/DIN1, or MUXOUT2 and A/DIN2 it may be necessary to protect these pins. The voltage at these pins should not exceed VA+ or go below AGND (see Figure

> This is the positive analog voltage reference input. In order to maintain accuracy the voltage range of  $V_{REF}$  ( $V_{REF} = V_{REF} + - V_{REF}$ ) is

CONV

COM

A/DIN1. A/DIN2

 $V_{REF}$ +

# Pin Descriptions (Continued) 1 V<sub>DC</sub>to 3.3 V<sub>DC</sub> and the voltage at V<sub>REF</sub>+ cannot exceed V<sub>A</sub>+. See Figure 6 for recommended bypassing. V<sub>REF</sub> The negative voltage reference input. In order to maintain accuracy the voltage at this pin must not go below GND or exceed V<sub>A</sub>+. (See Figure 6). V<sub>A</sub>+, V<sub>D</sub>+ These are the analog and digital power supply pins. V<sub>A</sub>+ and V<sub>D</sub>+ are not connected together on the chip. These pins should be tied to the same power supply and bypassed separately (see Figure 6). The operating voltage range of V<sub>A</sub>+ and V<sub>D</sub>+ is 3.0 V<sub>DC</sub> to 5.5 V<sub>DC</sub>. DGND This is the digital ground pin (see Figure 6).

This is the analog ground pin (see Figure 6).

**AGND** 

### Absolute Maximum Ratings (Notes 1, 2)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

Positive Supply Voltage

 $(\mathsf{V}^+ = \mathsf{V}_\mathsf{A} + = \mathsf{V}_\mathsf{D} +)$ 6.5V

Voltage at Inputs and Outputs

except CH0-CH7 and COM -0.3V to  $V^+ +0.3V$ 

Voltage at Analog Inputs

CH0-CH7 and COM GND -5V to  $V^+ +5V$  $|V_A^+ - V_D^+|$ 300 mV Input Current at Any Pin (Note 3) ±30 mA

Package Input Current (Note 3) ±120 mA

Package Dissipation at

 $T_A = 25^{\circ}C \text{ (Note 4)}$ 500 mW

ESD Susceptability (Note 5)

Human Body Model 1500V

Soldering Information

260°C N Packages (10 seconds)

SO Package (Note 6):

215°C Vapor Phase (60 seconds) Infrared (15 seconds) 220°C -65°C to +150°C

Storage Temperature

### Operating Ratings (Notes 1, 2)

Operating Temperature Range

 $T_{MIN} \leq T_{A} \leq T_{MAX}$ 

ADC12L030CIWM, ADC12L032CIWM,

ADC12L034CIWM,

ADC12L038CIWM

 $-40^{\circ}C \leq T_{A} \leq +85^{\circ}C$ 

1V to V<sub>A</sub>+

0V to  $V_{A^+}$ 

Supply Voltage

 $(V^+ = V_A^+ = V_D^+)$ +3.0V to +5.5V

 $|V_A^+ - V_D^+|$ ≤ 100 mV 0V to V<sub>A</sub>+  $V_{\mathsf{REF}^+}$ 0V to  $V_{\text{REF}}$ +

 $V_{\mathsf{REF}^-}$  $V_{REF} (V_{REF} + V_{REF})$ 

V<sub>REF</sub> Common Mode Voltage Range

 $(V_{REF}^+ + V_{REF}^-)$ 

A/DIN1, A/DIN2, MUXOUT1

and MUXOUT2 Voltage Range

A/D IN Common Mode Voltage Range

 $(V_{IN}^+ + V_{IN}^-)$ 

### Converter Electrical Characteristics

The following specifications apply for  $V^+ = V_A + = V_D + = +3.3 \ V_{DC}$ ,  $V_{REF} + = +2.500 \ V_{DC}$ ,  $V_{REF} - = 0 \ V_{DC}$ , 12-bit + sign conversion mode,  $t_{CK} = t_{SK} = 5 \ \text{MHz}$ ,  $R_S = 25\Omega$ , source impedance for  $V_{REF} + \text{and} \ V_{REF} - \le 25\Omega$ , fully-differential input with fixed 1.250V common-mode voltage, and  $10(t_{CK})$  acquisition time unless otherwise specified. **Boldface limits apply for T\_A = T\_J = T\_{MIN} to T\_{MAX}**; all other limits  $T_A = T_J = 25 \ \text{C}$ . (Notes 7, 8, 9)

Symbol	Parameter	Conditions	Typical (Note 10)	Limits (Note 11)	Units (Limits)
STATIC C	ONVERTER CHARACTERISTICS	•			
	Resolution with No Missing Codes			12 + sign	Bits (min)
+ILE	Positive Integral Linearity Error	After Auto-Cal (Notes 12, 18)	±1/2	±1	LSB (max)
-ILE	Negative Integral Linearity Error	After Auto-Cal (Notes 12, 18)	±1/2	±1	LSB (max)
DNL	Differential Non-Linearity	After Auto-Cal		±1	LSB (max)
	Positive Full-Scale Error	After Auto-Cal (Notes 12, 18)	±1/2	±2	LSB (max)
	Negative Full-Scale Error	After Auto-Cal (Notes 12, 18)	±1/2	±2	LSB (max)
	Offset Error	After Auto-Cal (Notes 5, 18)	±1/2	±2	LSB (max)
		$V_{IN}(+) = V_{IN}(-) = 1.250V$			
	DC Common Mode Error	After Auto-Cal (Note 15)	±2	±3.5	LSB (max)
TUE	Total Unadjusted Error	After Auto-Cal	±1		LSB
		(Notes 12, 13, 14)			
	Resolution with No Missing Codes	8-bit + sign mode		8 + sign	Bits (min)
+INL	Positive Integral Linearity Error	8-bit + sign mode (Note 12)		±1/2	LSB (max)
-INL	Negative Integral Linearity Error	8-bit + sign mode (Note 12)		±1/2	LSB (max)
DNL	Differential Non-Linearity	8-bit + sign mode		±3/4	LSB (max)
	Positive Full-Scale Error	8-bit + sign mode (Note 12)		±1/2	LSB (max)
	Negative Full-Scale Error	8-bit + sign mode (Note 12)		±1/2	LSB (max)
	Offset Error	8-bit + sign mode,			
		after Auto-Zero (Note 13)		±1/2	LSB (max)
		$V_{IN}(+) = V_{IN}(-) = + 1.250V$			
TUE	Total Unadjusted Error	8-bit + sign mode			
		after Auto-Zero		±3/4	LSB (max)
		(Notes 12, 13, 14)			
		(110103 12, 10, 14)			l

### **Converter Electrical Characteristics** (Continued)

The following specifications apply for  $V^+ = V_A + = V_D + = +3.3 \ V_{DC}, V_{REF} + = +2.500 \ V_{DC}, V_{REF} = 0 \ V_{DC}, 12-bit + sign conversion mode, <math>f_{CK} = f_{SK} = 5 \ MHz$ ,  $R_S = 25\Omega$ , source impedance for  $V_{REF} +$  and  $V_{REF} - \le 25\Omega$ , fully-differential input with fixed 1.250V common-mode voltage, and  $10(t_{CK})$  acquisition time unless otherwise specified. **Boldface limits apply for T\_A = T\_J = T\_{MIN} to T\_{MAX}**; all other limits  $T_A = T_J = 25 \ C$ . (Notes 7, 8, 9)

Multiplexer Channel to Channel Matching Power Supply Sensitivity  Offset Error + Full-Scale Error - Full-Scale Error - Integral Linearity Error - Integral Linearity Error Output Data from "12-Bit Conversion of Offset" (see Table 5) Output Data from "12-Bit Conversion of Full-Scale" (see Table 5)  DYNAMIC CONVERTER CHARACTE Signal-to-Noise Plus Distortion Ratio	$V^{+} = +3.3V \pm 10\%$ (Note 20)  (Note 20)  RISTICS $f_{IN} = 1 \text{ kHz, } V_{IN} = 2.5 \text{ V}_{PP}$	±0.05 ±0.5 ±0.5 ±0.5 ±0.5 ±0.5	±1 ±1.5 ±1.5 ±1.5 ±10 –10 4095 4093	LSB (max) LSB (max) LSB (max) LSB (SB (max) LSB (Max) LSB (Min) LSB (min)
Matching  Power Supply Sensitivity  Offset Error  + Full-Scale Error  - Full-Scale Error  + Integral Linearity Error  - Integral Linearity Error  Output Data from  "12-Bit Conversion of Offset" (see Table 5)  Output Data from  "12-Bit Conversion of Full-Scale" (see Table 5)  DYNAMIC CONVERTER CHARACTE  Signal-to-Noise Plus	(Note 20) (Note 20)	±0.5 ±0.5 ±0.5 ±0.5	±1.5 ±1.5 +10 -10	LSB (max) LSB (max) LSB (max) LSB LSB (max) LSB (min) LSB (min)
Power Supply Sensitivity  Offset Error  + Full-Scale Error  - Full-Scale Error  + Integral Linearity Error  - Integral Linearity Error  Output Data from  "12-Bit Conversion of Offset" (see Table 5)  Output Data from  "12-Bit Conversion of Full-Scale" (see Table 5)  DYNAMIC CONVERTER CHARACTE  Signal-to-Noise Plus	(Note 20) (Note 20)	±0.5 ±0.5 ±0.5	±1.5 ±1.5 +10 -10	LSB (max LSB (max LSB LSB (max LSB (min)
Offset Error + Full-Scale Error - Full-Scale Error - Integral Linearity Error - Integral Linearity Error Output Data from "12-Bit Conversion of Offset" (see Table 5) Output Data from "12-Bit Conversion of Full-Scale" (see Table 5)  DYNAMIC CONVERTER CHARACTE Signal-to-Noise Plus	(Note 20) (Note 20)	±0.5 ±0.5 ±0.5	±1.5 ±1.5 +10 -10	LSB (max LSB (max LSB LSB (max LSB (min)
+ Full-Scale Error - Full-Scale Error - Full-Scale Error + Integral Linearity Error - Integral Linearity Error Output Data from "12-Bit Conversion of Offset" (see Table 5) Output Data from "12-Bit Conversion of Full-Scale" (see Table 5)  DYNAMIC CONVERTER CHARACTE Signal-to-Noise Plus	(Note 20)	±0.5 ±0.5 ±0.5	±1.5 ±1.5 +10 -10	LSB (max LSB (max LSB LSB (max LSB (min)
- Full-Scale Error + Integral Linearity Error - Integral Linearity Error Output Data from "12-Bit Conversion of Offset" (see <i>Table 5</i> ) Output Data from "12-Bit Conversion of Full-Scale" (see <i>Table 5</i> )  DYNAMIC CONVERTER CHARACTE Signal-to-Noise Plus	(Note 20)	±0.5 ±0.5	±1.5 +10 -10	LSB (max LSB LSB (max LSB (min
+ Integral Linearity Error - Integral Linearity Error Output Data from "12-Bit Conversion of Offset" (see <i>Table 5</i> ) Output Data from "12-Bit Conversion of Full-Scale" (see <i>Table 5</i> )  DYNAMIC CONVERTER CHARACTE Signal-to-Noise Plus	(Note 20)	±0.5	+10 -10 4095	LSB LSB (max LSB (min
- Integral Linearity Error  Output Data from  "12-Bit Conversion of Offset" (see Table 5)  Output Data from  "12-Bit Conversion of Full-Scale" (see Table 5)  DYNAMIC CONVERTER CHARACTE  Signal-to-Noise Plus	(Note 20)		-10 4095	LSB (max LSB (max
Output Data from  "12-Bit Conversion of Offset" (see <i>Table 5</i> ) Output Data from  "12-Bit Conversion of Full-Scale" (see <i>Table 5</i> )  DYNAMIC CONVERTER CHARACTE Signal-to-Noise Plus	(Note 20)	±0.5	-10 4095	LSB (max LSB (min
"12-Bit Conversion of Offset" (see Table 5) Output Data from "12-Bit Conversion of Full-Scale" (see Table 5)  DYNAMIC CONVERTER CHARACTE Signal-to-Noise Plus	(Note 20)		-10 4095	LSB (min
(see <i>Table 5</i> ) Output Data from "12-Bit Conversion of Full-Scale" (see <i>Table 5</i> )  DYNAMIC CONVERTER CHARACTE Signal-to-Noise Plus	RISTICS		4095	LSB (max
Output Data from  "12-Bit Conversion of Full-Scale" (see <i>Table 5</i> )  DYNAMIC CONVERTER CHARACTE Signal-to-Noise Plus	RISTICS			*
"12-Bit Conversion of Full-Scale" (see <i>Table 5</i> )  DYNAMIC CONVERTER CHARACTE  Signal-to-Noise Plus	RISTICS			•
(see <i>Table 5</i> ) <b>DYNAMIC CONVERTER CHARACTE</b> Signal-to-Noise Plus			4093	LSB (min)
DYNAMIC CONVERTER CHARACTE Signal-to-Noise Plus				
Signal-to-Noise Plus				
·	f - 1 kHz V - 25 V			
Distortion Ratio	IIN - I KIIZ, VIN - Z.3 VPP	69.4		dB
	f <sub>IN</sub> = 20 kHz, V <sub>IN</sub> = 2.5 V <sub>PP</sub>	68.3		dB
	f <sub>IN</sub> = 40 kHz, V <sub>IN</sub> = 2.5 V <sub>PP</sub>	65.7		dB
-3 dB Full Power Bandwidth	$V_{IN} = 2.5 V_{PP}$ , where S/(N+D)	31		kHz
	drops 3 dB			
TIAL DYNAMIC CONVERTER CHARA				
Signal-to-Noise Plus	$f_{IN} = 1 \text{ kHz}, V_{IN} = \pm 2.5 \text{V}$	77.0		dB
Distortion Ratio	$f_{IN} = 20 \text{ kHz}, V_{IN} = \pm 2.5 \text{V}$	73.9		dB
	$f_{IN} = 40 \text{ kHz}, V_{IN} = \pm 2.5 \text{V}$	67.0		dB
–3 dB Full Power Bandwidth	$V_{IN} = \pm 2.5V$ , where S/(N+D) drops 3 dB	40		kHz
I E INPUT, ANALOG INPUTS AND MU	<u>'</u>	-	1	
Reference Input Capacitance		85		pF
A/DIN1 and A/DIN2 Analog Input		75		pF
Capacitance				
A/DIN1 and A/DIN2 Analog Input	$V_{INI} = +3.3V$ or	±0.1	±1.0	μ <b>A</b> (max)
Leakage Current				, , ,
CH0-CH7 and COM Input Voltage			GND - 0.05	V (min)
			V <sub>A+</sub> + 0.05	V (max)
CH0-CH7 and COM Input		10		pF
·		20		pF
	On Channel = 3.3V and		-0.3	μA (min)
		3.01	3.0	L ()
		0.01	0.3	μ <b>A</b> (max)
				p (c/)
On Channel Leakage (Note 16)		0.01	0.3	μ <b>A</b> (max)
• ' '		0.01	0.5	μι (παλ)
STIS STIT GITA GOINT TITIS		_0.01	_03	μ <b>A</b> (min)
				μι (111111)
	TAL DYNAMIC CONVERTER CHARA Signal-to-Noise Plus Distortion Ratio  -3 dB Full Power Bandwidth  E INPUT, ANALOG INPUTS AND MU Reference Input Capacitance A/DIN1 and A/DIN2 Analog Input Capacitance A/DIN1 and A/DIN2 Analog Input Leakage Current CH0—CH7 and COM Input Voltage	$ \begin{array}{c} \text{-3 dB Full Power Bandwidth} & V_{\text{IN}} = 2.5 \text{ V}_{\text{PP}}, \text{ where S/(N+D)} \\ \text{drops 3 dB} \\ \hline \text{TAL DYNAMIC CONVERTER CHARACTERISTICS} \\ \text{Signal-to-Noise Plus} & f_{\text{IN}} = 1 \text{ kHz, V}_{\text{IN}} = \pm 2.5 \text{V} \\ \text{f}_{\text{IN}} = 20 \text{ kHz, V}_{\text{IN}} = \pm 2.5 \text{V} \\ \text{f}_{\text{IN}} = 40 \text{ kHz, V}_{\text{IN}} = \pm 2.5 \text{V} \\ \text{drops 3 dB} \\ \hline \text{E INPUT, ANALOG INPUTS AND MULTIPLEXER CHARACTERISTICS} \\ \hline \text{Reference Input Capacitance} \\ \hline \text{A/DIN1 and A/DIN2 Analog Input} \\ \hline \text{Capacitance} \\ \hline \text{A/DIN1 and A/DIN2 Analog Input} \\ \hline \text{CHO-CH7 and COM Input Voltage} \\ \hline \text{CHO-CH7 and COM Input Capacitance} \\ \hline \text{MUX Output Capacitance} \\ \hline \text{MUX Output Capacitance} \\ \hline \text{Off Channel Leakage (Note 16)} \\ \hline \text{On Channel = 3.3V and} \\ \hline \text{Off Channel Leakage (Note 16)} \\ \hline \text{On Channel = 3.3V and} \\ \hline \\ \hline \text{On Channel = 3.3V and} \\ \hline \\ \hline \text{On Channel = 3.3V and} \\ \hline \\ \hline \text{On Channel = 3.3V and} \\ \hline \\ \hline \text{On Channel = 3.3V and} \\ \hline \\ \hline \text{On Channel = 3.3V and} \\ \hline \\ \hline \text{On Channel = 3.3V and} \\ \hline \\ \hline \text{On Channel = 3.3V and} \\ \hline \\ \hline \text{On Channel = 3.3V and} \\ \hline \\ \hline \text{On Channel = 3.3V and} \\ \hline \\ \hline \\ \hline On Channel Envertical Envertic$	3 dB Full Power Bandwidth	31

### **Converter Electrical Characteristics** (Continued)

The following specifications apply for  $V^+ = V_A + = V_D + = +3.3 \ V_{DC}$ ,  $V_{REF} + = +2.500 \ V_{DC}$ ,  $V_{REF} - = 0 \ V_{DC}$ , 12-bit + sign conversion mode,  $f_{CK} = f_{SK} = 5 \ \text{MHz}$ ,  $R_S = 25\Omega$ , source impedance for  $V_{REF} + \text{and} \ V_{REF} - \le 25\Omega$ , fully-differential input with fixed 1.250V common-mode voltage, and  $10(t_{CK})$  acquisition time unless otherwise specified. **Boldface limits apply for T\_A = T\_J = T\_{MIN} to T\_{MAX}**; all other limits  $T_A = T_J = 25 \ \text{C}$ . (Notes 7, 8, 9)

Symbol	Parameter	Conditions	<b>Typical</b> (Note 10)	<b>Limits</b> (Note 11)	Units (Limits)
REFEREN	ICE INPUT, ANALOG INPUTS AND MU	LTIPLEXER CHARACTERISTICS			
	MUXOUT1 and MUXOUT2	V <sub>MUXOUT</sub> = 3.3V or	0.01	0.3	μA (max)
	Leakage Current	V <sub>MUXOUT</sub> = 0V			
R <sub>ON</sub>	MUX On Resistance	V <sub>IN</sub> = 1.65V and	1300	1900	Ω (max)
		V <sub>MUXOUT</sub> = 1.55V			
	R <sub>ON</sub> Matching Channel to Channel	V <sub>IN</sub> = 1.65V and	5		%
		V <sub>MUXOUT</sub> = 1.55V			
	Channel to Channel Crosstalk	$V_{IN} = 3.3 V_{PP}, f_{IN} = 40 \text{ kHz}$	-72	·	dB
	MUX Bandwidth		90		kHz

DC and Logic Electrical Characteristics 
The following specifications apply for  $V^+ = V_A + = V_D + = +3.3 \ V_{DC}, V_{REF} + = +2.500 \ V_{DC}, V_{REF} = = 0 \ V_{DC}, 12-bit + sign conversion mode, <math>t_{CK} = t_{SK} = 5 \ MHz, R_S = 25\Omega$ , source impedance for  $V_{REF} + \text{and } V_{REF} \le 25\Omega$ , fully-differential input with fixed 1.250V common-mode voltage, and 10( $t_{CK}$ ) acquisition time unless otherwise specified. Boldface limits apply for  $T_A = T_J = T_{MIN}$  to  $T_{MAX}$ ; all other limits  $T_A = T_J = 25 \ C$ . (Notes 7, 8, 9)

Symbol	Parameter	Conditions	Typical	Limits	Units
			(Note 10)	(Note 11)	(Limits)
CCLK, C	S, CONV, DI, PD AND SCLK INPUT C	HARACTERISTICS	•		
V <sub>IN(1)</sub>	Logical "1" Input Voltage	V <sup>+</sup> = 3.6V		2.0	V (min)
V <sub>IN(0)</sub>	Logical "0" Input Voltage	V <sup>+</sup> = 3.0V		0.8	V (max)
I <sub>IN(1)</sub>	Logical "1" Input Current	V <sub>IN</sub> = 3.3V	0.005	1.0	μA (max)
I <sub>IN(0)</sub>	Logical "0" Input Current	V <sub>IN</sub> = 0V	-0.005	-1.0	μA (min)
DO, EO	AND DOR DIGITAL OUTPUT CHARA	CTERISTICS			
V <sub>OUT(1)</sub>	Logical "1" Output Voltage	$V^{+} = 3.0V, I_{OUT} = -360 \mu A$		2.4	V (min)
		$V^{+} = 3.0V$ , $I_{OUT} = -10 \mu A$		2.9	V (min)
V <sub>OUT(0)</sub>	Logical "0" Output Voltage	V <sup>+</sup> = 3.0V, I <sub>OUT</sub> = 1.6 mA		0.4	V (max)
I <sub>OUT</sub>	TRI-STATE® Output Current	V <sub>OUT</sub> = 0V	-0.1	-3.0	μA (max)
		V <sub>OUT</sub> = 3.3V	0.1	3.0	μA (max)
+l <sub>sc</sub>	Output Short Circuit Source Current	V <sub>OUT</sub> = 0V	14	6.5	mA (min)
-I <sub>sc</sub>	Output Short Circuit Sink Current	$V_{OUT} = V_{D} +$	16	8.0	mA (min)
POWER	SUPPLY CHARACTERISTICS				
I <sub>D</sub> +	Digital Supply Current	Awake	1.1	1.5	mA (max)
		CS = HIGH, Powered Down, CCLK on	600		μΑ
		CS = HIGH, Powered Down, CCLK off	12		μΑ
I <sub>A</sub> +	Positive Analog Supply Current	Awake	2.2	3.0	mA (max)
		CS = HIGH, Powered Down, CCLK on	10		μΑ
		CS = HIGH, Powered Down, CCLK off	0.1		μΑ
I <sub>REF</sub>	Reference Input Current	Awake	70		μΑ
		CS = HIGH, Powered Down	0.1		μΑ

### **AC Electrical Characteristics**

The following specifications apply for  $V^+ = V_{A^+} = V_{D^+} = +3.3 \ V_{DC}$ ,  $V_{REF^+} = +2.500 \ V_{DC}$ ,  $V_{REF^-} = 0 \ V_{DC}$ , 12-bit + sign conversion mode,  $t_r = t_r = 3 \ ns$ ,  $t_{CK} = t_{SK} = 5 \ MHz$ ,  $R_S = 25\Omega$ , source impedance for  $V_{REF^+}$  and  $V_{REF^-} \leq 25\Omega$ , fully-differential input with fixed 1.250V common-mode voltage, and  $10(t_{CK})$  acquisition time unless otherwise specified. **Boldface limits apply for T\_A = T\_J = T\_{MIN} to T\_{MAX}**; all other limits  $T_A = T_J = 25 \ C$ . (Note 17)

Symbol	Parameter	Conditions	Typical	Limits	Units
			(Note 10)	(Note 11)	(Limits)
f <sub>CK</sub>	Conversion Clock (CCLK) Frequency		10	5	MHz (max
			1		MHz (mir
f <sub>sk</sub>	Serial Data Clock SCLK Frequency		10	5	MHz (max
	, ,		0		Hz (min)
	Conversion Clock Duty Cycle			40	% (min)
	, ,			60	% (max)
	Serial Data Clock Duty Cycle			40	% (min)
	Solidi Bala Sissik Baly Sysie			60	% (max)
t <sub>c</sub>	Conversion Time	12-Bit + Sign or 12-Bit	44(t <sub>CK</sub> )	44(t <sub>CK</sub> )	(max)
'C	Genversion Time	TE BIL + OIGH OF TE BIL	++('CK)	8.8	, ,
		9 Bit . Sign or 9 Bit	21/+ )	+	μs (max)
		8-Bit + Sign or 8-Bit	21(t <sub>CK</sub> )	21(t <sub>CK</sub> )	(max)
_	Association Time	C Cualan Dunananan	6(4 )	4.2	μs (max)
t <sub>A</sub>	Acquisition Time	6 Cycles Programmed	6(t <sub>CK</sub> )	6(t <sub>CK</sub> )	(min)
	(Note 19)			7(t <sub>CK</sub> )	(max)
				1.2	μs (min)
				1.4	μs (max
		10 Cycles Programmed	10(t <sub>CK</sub> )	10(t <sub>CK</sub> )	(min)
				11(t <sub>CK</sub> )	(max)
				2.0	μs (min)
				2.2	μs (max
		18 Cycles Programmed	18(t <sub>CK</sub> )	18(t <sub>CK</sub> )	(min)
				19(t <sub>CK</sub> )	(max)
				3.6	μs (min)
				3.8	μs (max
		34 Cycles Programmed	34(t <sub>CK</sub> )	34(t <sub>CK</sub> )	(min)
				35(t <sub>CK</sub> )	(max)
				6.8	μs (min)
				7.0	μs (max
t <sub>CAL</sub>	Self-Calibration Time		4944(t <sub>CK</sub> )	4944(t <sub>CK</sub> )	(max)
			1 3.0	988.8	μs (max
t <sub>AZ</sub>	Auto-Zero Time		76(t <sub>CK</sub> )	76(t <sub>CK</sub> )	(max)
72			( 6/0	15.2	μs (max
t <sub>SYNC</sub>	Self-Calibration or Auto-Zero		2(t <sub>CK</sub> )	2(t <sub>CK</sub> )	(min)
SYNC	Synchronization Time		Z(CK)	3(t <sub>CK</sub> )	(max)
	from DOR			0.40	μs (min)
				0.60	μs (max
+	DOR High Time when CS is Low		9/+ \		
t <sub>DOR</sub>	Continuously		9(t <sub>sk</sub> )	9(t <sub>sK</sub> )	(max)
	for Read Data and Software Power Up/Down			1.8	μs (max
t <sub>conv</sub>	CONV Valid Data Time		8(t <sub>sk</sub> )	8(t <sub>sk</sub> )	(max)
				1.6	μs (max
t <sub>HPU</sub>	Hardware Power-Up Time, Time from		250	700	μs (max
0	PD Falling Edge to EOC Rising Edge	1		1	' '

### **AC Electrical Characteristics** (Continued)

The following specifications apply for  $V^+ = V_{A^+} = V_{D^+} = +3.3~V_{DC},~V_{REF^+} = +2.500~V_{DC},~V_{REF^-} = 0~V_{DC},~12\text{-bit}$  + sign conversion mode,  $t_r = t_r = 3~\text{ns},~f_{CK} = f_{SK} = 5~\text{MHz},~R_S = 25\Omega,~\text{source impedance for}~V_{REF^+}$  and  $V_{REF^-} \leq 25\Omega,~\text{fully-differential input}$  with fixed 1.250V common-mode voltage, and  $10(t_{CK})$  acquisition time unless otherwise specified. Boldface limits apply for  $T_A = T_J = T_{MIN}~\text{to}~T_{MAX};~\text{all other limits}~T_A = T_J = 25~\text{C}.~\text{(Note 17)}$ 

Symbol	Parameter	Conditions	Typical	Limits	Units
			(Note 10)	(Note 11)	(Limits)
t <sub>spu</sub>	Software Power-Up Time, Time from				
	Serial Data Clock Falling Edge to		500	700	μs (max)
	EOC Rising Edge				
t <sub>ACC</sub>	Access Time Delay from		25	60	ns (max)
	CS Falling Edge to DO Data Valid				
t <sub>SET-UP</sub>	Set-Up Time of CS Falling Edge to			50	ns (min)
	Serial Data Clock Rising Edge				
t <sub>DELAY</sub>	Delay from SCLK Falling		0	5	ns (min)
	Edge to CS Falling Edge				
t <sub>1H</sub> , t <sub>OH</sub>	Delay from CS Rising Edge to	R <sub>L</sub> = 3k, C <sub>L</sub> = 100 pF	70	100	ns (max)
	DO TRI-STATE				
t <sub>HDI</sub>	DI Hold Time from Serial Data		5	15	ns (min)
	Clock Rising Edge				
t <sub>SDI</sub>	DI Set-Up Time from Serial Data		5	10	ns (min)
	Clock Rising Edge				
t <sub>HDO</sub>	DO Hold Time from Serial Data	$R_L = 3k, C_L = 100 pF$	35	65	ns (max)
	Clock Falling Edge			5	ns (min)
t <sub>DDO</sub>	Delay from Serial Data Clock		50	90	ns (max)
	Falling Edge to DO Data Valid				
t <sub>RDO</sub>	DO Rise Time, TRI-STATE to High	$R_L = 3k, C_L = 100 pF$	10	40	ns (max)
	DO Rise Time, Low to High		10	40	ns (max)
t <sub>FDO</sub>	DO Fall Time, TRI-STATE to Low	$R_L = 3k, C_L = 100 pF$	15	40	ns (max)
	DO Fall Time, High to Low		15	40	ns (max)
t <sub>CD</sub>	Delay from CS Falling Edge		50	80	ns (max)
	to DOR Falling Edge				l
t <sub>SD</sub>	Delay from Serial Data Clock Falling		45	80	ns (max)
	Edge to DOR Rising Edge				l
C <sub>IN</sub>	Capacitance of Logic Inputs		10		pF
C <sub>OUT</sub>	Capacitance of Logic Outputs		20		pF

Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.

Note 2: All voltages are measured with respect to GND, unless otherwise specified.

Note 3: When the input voltage  $(V_{IN})$  at any pin exceeds the power supplies  $(V_{IN} < \text{GND or } V_{IN} > V_{A^+} \text{ or } V_{D^+})$ , the current at that pin should be limited to 20 mA. The 120 mA maximum package input current rating limits the number of pins that can safely exceed the power supplies with an input current of 20 mA to four.

Note 4: The maximum power dissipation must be derated at elevated temperatures and is dictated by  $T_J max$ ,  $\theta_{JA}$  and the ambient temperature,  $T_A$ . The maximum allowable power dissipation at any temperature is  $P_D = (T_J max - T_A)/\theta_{JA}$  or the number given in the Absolute Maximum Ratings, whichever is lower. For this device,  $T_J max = 150^{\circ}C$ . The typical thermal resistance ( $\theta_{JA}$ ) of these parts when board mounted follow:

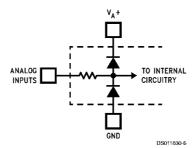
### AC Electrical Characteristics (Continued)

Part Number	Thermal Resistance θ <sub>JA</sub>
ADC12L030CIWM	70°C/W
ADC12L032CIWM	64°C/W
ADC12L034CIWM	57°C/W
ADC12L038CIWM	50°C/W

Note 5: The human body model is a 100 pF capacitor discharged through a 1.5 k $\Omega$  resistor into each pin.

Note 6: See AN450 "Surface Mounting Methods and Their Effect on Product Reliability" or the section titled "Surface Mount" found in any post 1986 National Semi-conductor Linear Data Book for other methods of soldering surface mount devices.

Note 7: Two on-chip diodes are tied to each analog input through a series resistor as shown below. Input voltage magnitude up to 5V above  $V_{A^+}$  or 5V below GND will not damage this device. However, errors in the A/D conversion can occur (if these diodes are forward biased by more than 50 mV) if the input voltage magnitude of selected or unselected analog input go above  $V_{A^+}$  or below GND by more than 50 mV. As an example, if  $V_{A^+}$  is 3.0  $V_{DC}$ , full-scale input voltage must be  $\leq$ 3.05  $V_{DC}$  to ensure accurate conversions.



Note 8: To guarantee accuracy, it is required that the V<sub>A</sub>+ and V<sub>D</sub>+ be connected together to the same power supply with separate bypass capacitors at each V<sup>+</sup> pin.

Note 9: With the test condition for  $V_{REF}$  ( $V_{REF}$  –  $V_{REF}$  ) given as +2.500V the 12-bit LSB is 610  $\mu$ V and the 8-bit LSB is 9.8 mV.

Note 10: Typicals are at  $T_J = T_A = 25^{\circ}C$  and represent most likely parametric norm

Note 11: Tested limits are guaranteed to National's AOQL (Average Outgoing Quality Level).

Note 12: Positive integral linearity error is defined as the deviation of the analog value, expressed in LSBs, from the straight line that passes through positive full-scale and zero. For negative integral linearity error, the straight line passes through negative full-scale and zero (see Figure 2 and Figure 3).

Note 13: Zero error is a measure of the deviation from the mid-scale voltage (a code of zero), expressed in LSB. It is the worst-case value of the code transitions between 1 to 0 and 0 to +1 (see Figure 4).

Note 14: Total unadjusted error includes offset, full-scale, linearity and multiplexer errors.

Note 15: The DC common-mode error is measured in the differential multiplexer mode with the assigned positive and negative input channels shorted together.

Note 16: Channel leakage current is measured after the channel selection.

Note 17: Timing specifications are tested at the TTL logic levels,  $V_{IL}$  = 0.4V for a falling edge and  $V_{IH}$  = 2.4V for a rising edge. TRI-STATE output voltage is forced to 1.4V.

Note 18: The ADC12L030 family's self-calibration technique ensures linearity and offset errors as specified, but noise inherent in the self-calibration process will result in a maximum repeatability uncertainty of 0.2 LSB.

Note 19: If SCLK and CCLK are driven from the same clock source, then t<sub>A</sub> is 6, 10, 18 or 34 clock periods minimum and maximum.

Note 20: The "12-Bit Conversion of Offset" and "12-Bit Conversion of Full-Scale" modes are intended to test the functionality of the device. Therefore, the output data from these modes are not an indication of the accuracy of a conversion result.

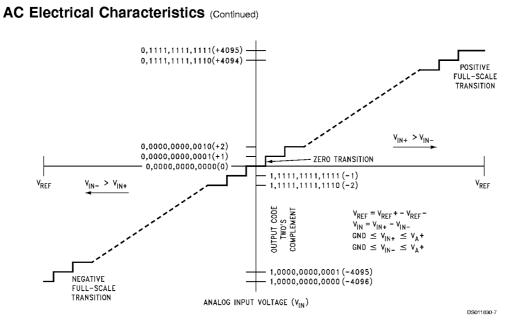


FIGURE 1. Transfer Characteristic

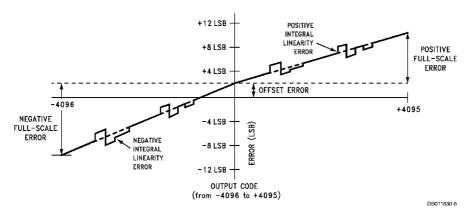


FIGURE 2. Simplified Error Curve vs Output Code without Auto-Calibration or Auto-Zero Cycles

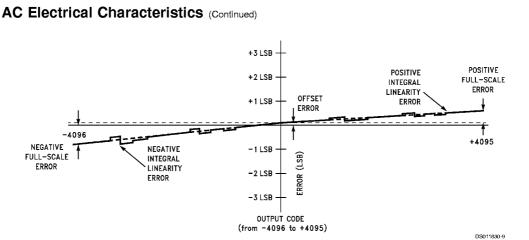


FIGURE 3. Simplified Error Curve vs Output Code after Auto-Calibration Cycle

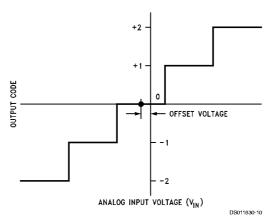
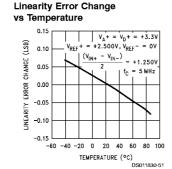
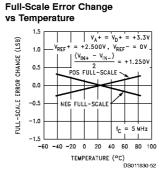
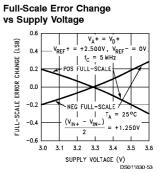


FIGURE 4. Offset or Zero Error Voltage

**Typical Performance Characteristics** The following curves apply for 12-bit + sign mode after auto-calibration unless otherwise specified. The performance for 8-bit + sign mode is equal to or better than shown. (Note 9)

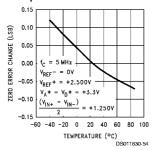




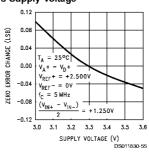


**Typical Performance Characteristics** The following curves apply for 12-bit + sign mode after auto-calibration unless otherwise specified. The performance for 8-bit + sign mode is equal to or better than shown. (Note 9) (Continued)

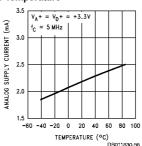
### Zero Error Change vs Temperature



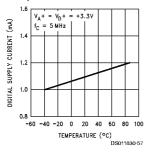
### Zero Error Change vs Supply Voltage



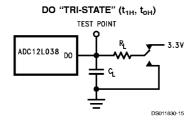
### Analog Supply Current vs Temperature



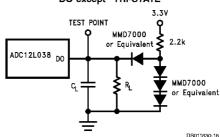
### Digital Supply Current vs Temperature

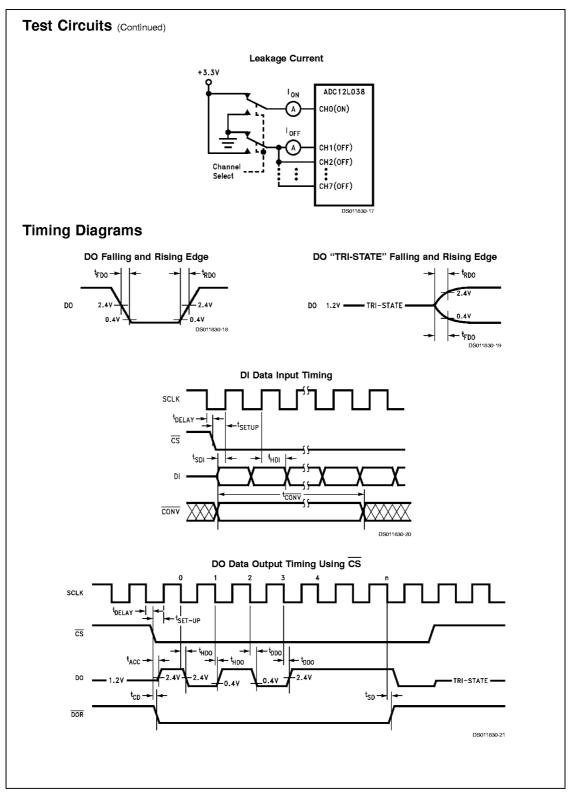


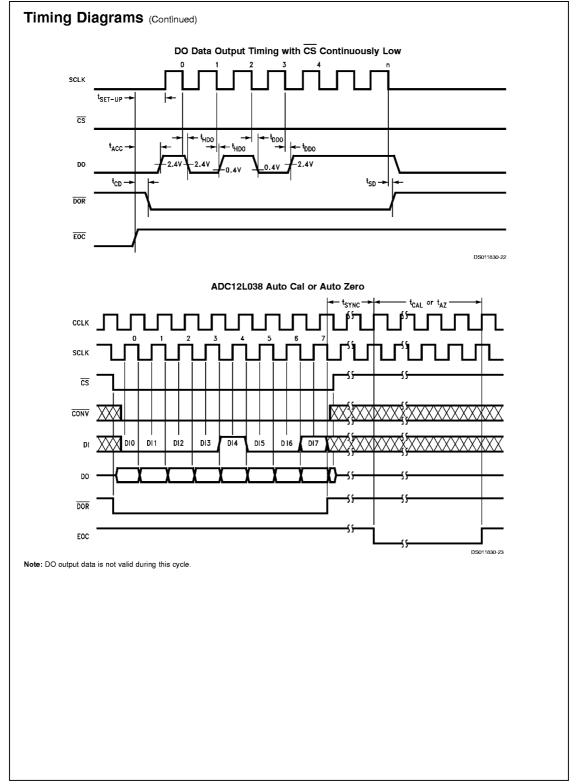
### **Test Circuits**

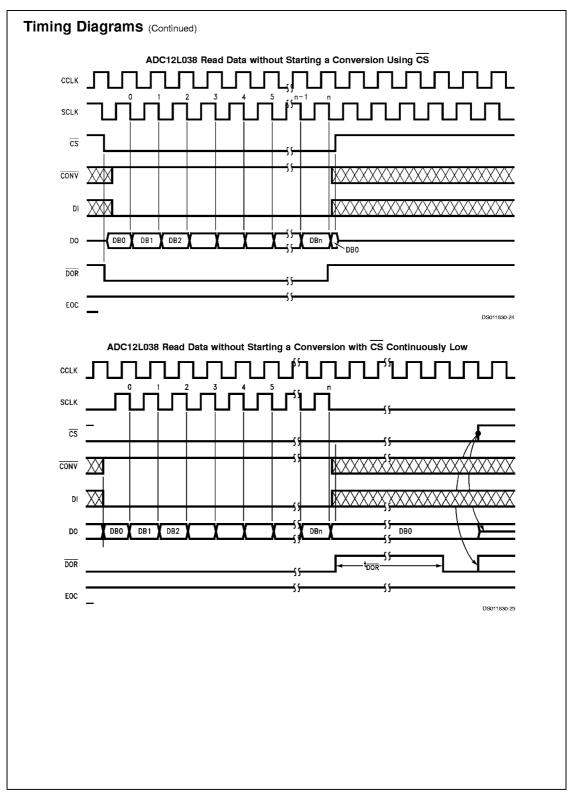


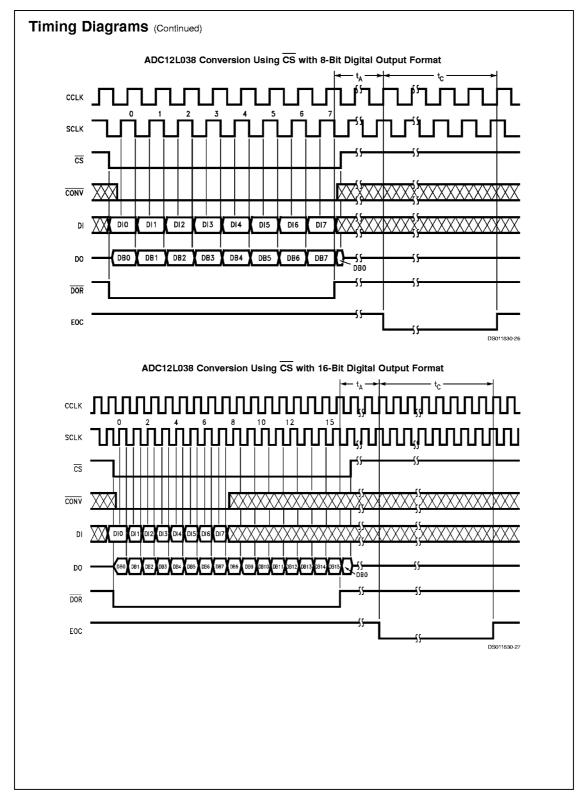
### DO except "TRI-STATE"

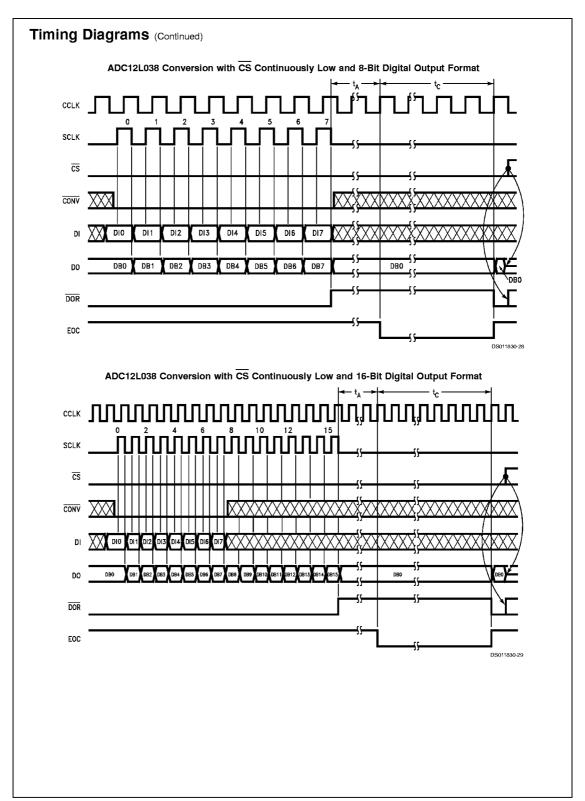


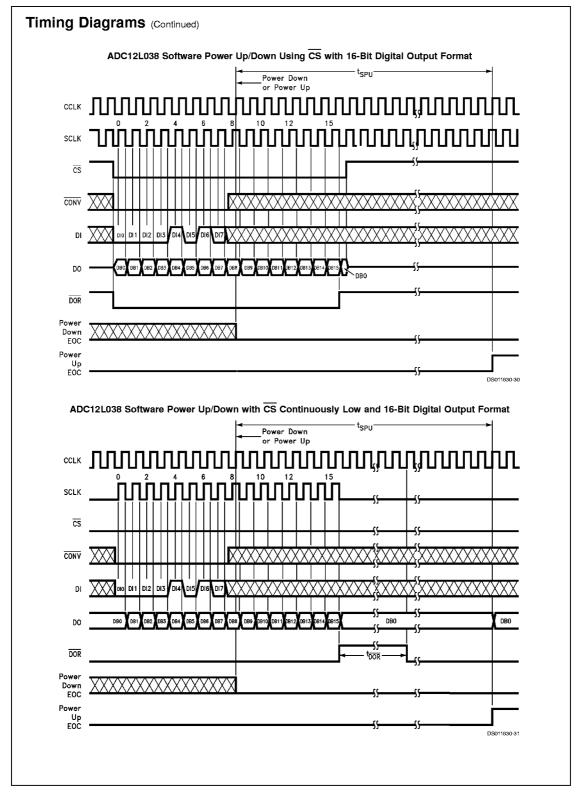


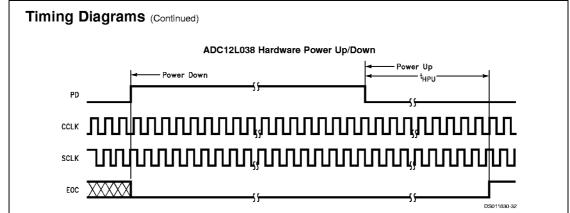






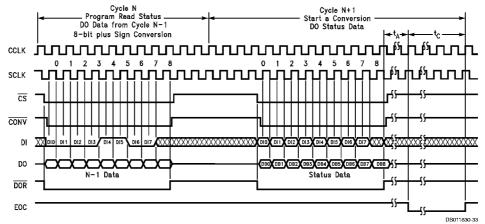






Note: Hardware power up/down may occur at any time. If PD is high while a conversion is in progress that conversion will be corrupted and erroneous data will be stored in the output shift register.

### ADC12L038 Configuration Modification — Example of a Status Read



Note: In order for all 9 bits of status information to be accessible the last conversion programmed before Cycle N needs to have a resolution of 8 bits plus sign, 12 bits, 12 bits plus sign, or greater.

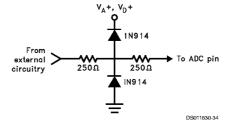
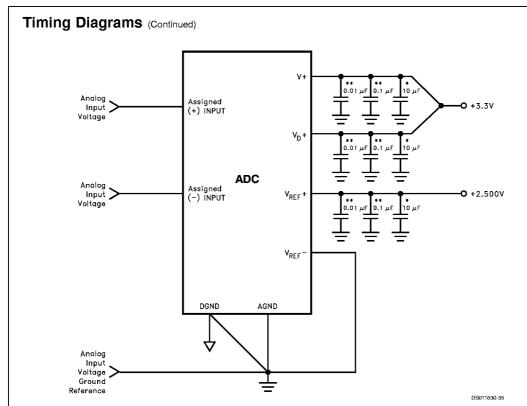


FIGURE 5. Protecting the MUXOUT1, MUXOUT2, A/DIN1 and A/DIN2 Analog Pins



<sup>\*</sup>Tantalum

\*\*Monolithic Ceramic or better

FIGURE 6. Recommended Power Supply Bypassing and Grounding

### **Tables**

TABLE 1. Data Out Formats

	O Format	s	DB0	DB1	DB2	DB3	DB4	DB5	DB6	DB7	DB8	DB9	DB10	DB11	DB12	DB13	DB14	DB15	DB16
with		17	X	Х	х	Х	Sign	MSB	10	9	8	7	6	5	4	3	2	1	LSB
Sign		Bits																	
	MSB	13	Sign	MSB	10	9	8	7	6	5	4	3	2	1	LSB				
	First	Bits																	
		9	Sign	MSB	6	5	4	3	2	1	LSB								
		Bits																	
		17	LSB	1	2	3	4	5	6	7	8	9	10	MSB	Sign	Х	Х	Х	Х
		Bits																	
	LSB	13	LSB	1	2	3	4	5	6	7	8	9	10	MSB	Sign				
	First	Bits																	
		9	LSB	1	2	3	4	5	6	MSB	Sign								
		Bits																	

### Tables (Continued)

TABLE 1. Data Out Formats (Continued)

DO Formats			DB0	DB1	DB2	DB3	DB4	DB5	DB6	DB7	DB8	DB9	DB10	DB11	DB12	DB13	DB14	DB15	DB16
without		16	0	0	0	0	MSB	10	9	8	7	6	5	4	3	2	1	LSB	
Sign		Bits																	
	MSB	12	MSB	10	9	8	7	6	5	4	3	2	1	LSB					
	First	Bits																	
		8	MSB	6	5	4	3	2	1	LSB									
		Bits																	
		16	LSB	1	2	3	4	5	6	7	8	9	10	MSB	0	0	0	0	
		Bits																	
	LSB	12	LSB	1	2	3	4	5	6	7	8	9	10	MSB					
	First	Bits																	
		8	LSB	1	2	3	4	5	6	MSB									
		Bits																	

X = High or Low state.

TABLE 2. ADC12L038 Multiplexer Addressing

						Ana	log Cl	nanne	I Addr	essed			A/D	Input	Multi	plexer	Mode
	M	IJΧ					and	Assig	nmen	t			Pola	arity	Ou	tput	
	Add	ress				with	A/DIN	1 tied	to MU	XOUT	1		Assig	nment	Cha	nnel	
			and A/DIN2 tied to MUXOUT2										Assig	nment			
DIO	DI1	DI2	DI3	CHO	CH1	CH2	СНЗ	CH4	CH5	CH6	CH7	сом	A/DIN1	A/DIN2	MUXOUT1	MUXOUT2	
L	L	L	L	+	-								+	-	CH0	CH1	
L	L	L	Н			+	-						+	_	CH2	CH3	
L	L	Н	L					+	-				+	-	CH4	CH5	
L	L	Н	Н							+	-		+	_	CH6	CH7	Differential
L	Н	L	L	-	+								-	+	CH0	CH1	
L	н	L	Н			-	+						-	+	CH2	CH3	
L	Н	Н	L					-	+				-	+	CH4	CH5	
L	Н	Н	Н							-	+		-	+	CH6	CH7	
Н	L	L	L	+								-	+	-	CH0	сом	
Н	L	L	Н			+						_	+	-	CH2	сом	
Н	L	Н	L					+				-	+	_	CH4	СОМ	
Н	L	Н	Н							+		_	+	_	CH6	сом	Single-Ended
Н	Н	L	L		+							-	+	_	CH1	сом	
Н	Н	L	Н				+					_	+	_	CH3	сом	
Н	Н	Н	L						+			-	+	_	CH5	сом	
Н	Н	Н	Н								+	-	+	_	CH7	сом	

### TABLE 3. ADC12L034 Multiplexer Addressing

	Analog Channel Addressed MUX and Assignment			A/D Input Polarity		olexer put	Mode						
/	Address with A/DIN1 tied to MUXOUT1		Assignment		Cha								
	and A/DIN2 tied to MUXOUT2		Assign		nment								
DIO	DI1	DI2	CH0	CH1	CH2	СНЗ	СОМ	A/DIN1	A/DIN2	MUXOUT1	MUXOUT2		
L	L	L	+	-				+	-	CH0	CH1		
L	L	Н			+	-		+	-	CH2	СНЗ	Differential	
L	Н	L	-	+				-	+	CH0	CH1		
L	Н	Н			-	+		-	+	CH2	СНЗ		
Н	L	L	+				-	+	-	CH0	COM		
Н	L	Н			+		-	+	-	CH2	COM	Single-Ended	
Н	Н	L		+			-	+	+ -		COM		
Н	Н	Η				+	-	+	-	CH3	COM		

### Tables (Continued)

TABLE 4. ADC12L032 and ADC12L030 Multiplexer Addressing

1	JX ress	a with A/[	g Channel Add and Assignmer DIN1 tied to MU DIN2 tied to MU	nt JXOUT1	Pola	A/D Input Polarity Assignment		Multiplexer Output Channel Assignment		
DIO	DI1	CH0	CH1	СОМ	A/DIN1	A/DIN2	MUXOUT1	MUXOUT2		
L	L	+	_		+	-	CH0	CH1	Differential	
L	Н	_	+		_	+	CH0	CH1		
Н	L	+		-	+	-	CH0	COM	Single-Ended	
Н	Н		+	_	+	-	CH1	COM		

Note 21: ADC12L030 does not have A/DIN1, A/DIN2, MUXOUT1 and MUXOUT2 pins.

### TABLE 5. Mode Programming

ADC12L038	DI0	DI1	DI2	DI3	DI4	DI5	DI6	DI7	Mode Selected	DO Format	
ADC12L034	DIO	DI1	DI2		DI3	DI4	DI5	DI6	(Current)	(next Conversion	
ADC12L030										Cycle)	
and	DIO	DI1			DI2	DI3	DI4	DI5			
ADC12L032											
	See	Tables	s 2, 3,	4	L	L	L	L	12 Bit Conversion	12 or 13 Bit MSB First	
	See	Tables	s 2, 3,	4	L	L	L	Н	12 Bit Conversion	16 or 17 Bit MSB First	
	See Tables 2, 3, 4		4	L	L	Н	Г	8 Bit Conversion	8 or 9 Bit MSB First		
	L	L	L	L	L	L	Н	Η	12 Bit Conversion of Full-Scale	12 or 13 Bit MSB First	
	See	Tables	s 2, 3,	4	L	Н	L	L	12 Bit Conversion	12 or 13 Bit LSB First	
	See	Tables	s 2, 3,	4	L	Н	L	Н	12 Bit Conversion	16 or 17 Bit LSB First	
	See	Tables	2, 3,	4	L	Н	Н	L	8 Bit Conversion	8 or 9 Bit LSB First	
	L	L	L	L	L	Н	Н	I	12 Bit Conversion of Offset	12 or 13 Bit LSB First	
	L	L	L	L	Н	L	L	L	Auto Cal	No Change	
	L	L	L	L	Н	L	L	Н	Auto Zero	No Change	
	L	L	L	L	Н	L	Н	L	Power Up	No Change	
	L	L	L	L	Н	L	Н	Н	Power Down	No Change	
	L	L	L	L	Н	Н	L	L	Read Status Register	No Change	
	L	L	L	L	Н	Н	L	Ι	Data Out without Sign	No Change	
	Н	L	L	L	Н	Н	L	Τ	Data Out with Sign	No Change	
	L	L	L	L	Н	Н	Н	Г	Acquisition Time—6 CCLK Cycles	No Change	
	L	Н	L	L	Н	Н	Н	L	Acquisition Time — 10 CCLK Cycles	No Change	
	Н	L	L	L	Н	Н	Н	L	Acquisition Time — 18 CCLK Cycles	No Change	
	Н	Н	L	L	Н	Н	Н	L	Acquisition Time — 34 CCLK Cycles	No Change	
	L	L	L	L	Н	Н	Н	Н	User Mode	No Change	
	H X X X H H H H			3							

X = Don't Care

Note 22: The A/D powers up with no Auto Cal, no Auto Zero, 10 CCLK acquisition time, 12-bit + sign conversion, power up, 12- or 13-bit MSB first and user mode.

### Tables (Continued)

TABLE 6. Conversion/Read Data Only Mode Programming

<del>cs</del>	CONV	PD	Mode
L	L	L	See <i>Table 5</i> for Mode
L	Н	L	Read Only (Previous DO Format)
			No Conversion
Н	Х	L	Idle
Х	Х	Н	Power Down

X = Don't Care

**TABLE 7. Status Register** 

Status									
Bit	DB0	DB1	DB2	DB3	DB4	DB5	DB6	DB7	DB8
Location									
Status	PU	PD	Cal	8 or 9	12 or 13	16 or 17	Sign	Justification	Test
Bit									Mode
	C	evice Statu	S		DO 0	Output Forn	nat Status		
Function	"High" indicates a Power Up Sequence is in progress	"High" indicates a Power Down Sequence is in progress	"High" indicates an Auto-Cal Sequence is in progress	"High" indicates an 8 or 9 bit format	"High" indicates a 12 or 13 bit format	"High" indicates a 16 or 17 bit format	"High" indicates that the sign bit is included. When "Low" the sign bit is not included.	When "High" the conversion result will be output MSB first. When "Low" the result will be output LSB first.	When "High" the device is in test mode. When "Low" the device is in user mode.

### **Application Hints**

1.0 DIGITAL INTERFACE

### 1.1 Interface Concepts

The example in Figure 7 shows a typical sequence of events after the power is applied to the ADC12L030/2/4/8:

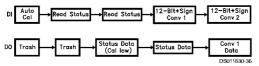


FIGURE 7. Typical Power Supply Power Up Sequence

The first instruction input to the A/D via DI initiates Auto Cal. The data output on DO at that time is meaningless and is completely random. To determine whether the Auto Cal has been completed, a read status instruction is issued to the A/D. Again the data output at that time has no significance since the Auto Cal procedure modifies the data in the output shift register. To retrieve the status information, an additional read status instruction is issued to the A/D. At this time the status data is available on DO. If the Cal signal in the status word is low Auto Cal has been completed. Therefore, the next instruction issued can start a conversion. The data output at this time is again status information. To keep noise from corrupting the A/D conversion, the status can not be read during a conversion, that conversion is prematurely ended.

EOC can be used to determine the end of a conversion or the A/D controller can keep track in software of when it would be appropriate to communicate to the A/D again. Once it has been determined that the A/D has completed a conversion another instruction can be transmitted to the A/D. The data from this conversion can be accessed when the next instruction is issued to the A/D.

Note, when  $\overline{CS}$  is low continuously it is important to transmit the exact number of SCLK cycles, as shown in the timing diagrams. Not doing so will desynchronize the serial communication to the A/D (see Section 1.3).

### 1.2 Changing Configuration

The configuration of the ADC12L030/2/4/8 on power up defaults to 12-bit plus sign resolution, 12- or 13-bit MSB First, 10 CCLK acquisition time, user mode, no Auto Cal, no Auto Zero, and power up mode. Changing the acquisition time and turning the sign bit on and off requires an 8-bit instruction to be issued to the ADC. This instruction will not start a conversion. The instructions that select a multiplexer address and format the output data do start a conversion. Figure 8 describes an example of changing the configuration of the ADC12L030/2/4/8.

During I/O sequence 1 the instruction on DI configures the ADC12L030/2/4/8 to do a conversion with 12-bit +sign resolution. Notice that when the 6 CCLK Acquisition and Data Out without Sign instructions are issued to the ADC, I/O sequences 2 and 3, a new conversion is not started. The data

output during these instructions is from conversion N which was started during I/O sequence 1. The Configuration Modification timing diagram describes in detail the sequence of events necessary for a Data Out without Sign, Data Out with Sign, or 6/10/18/34 CCLK Acquisition time mode selection.

Table 5 describes the actual data necessary to be input to the ADC to accomplish this configuration modification. The next instruction, shown in Figure 8, issued to the A/D starts conversion N+1 with 8 bits of resolution formatted MSB first. Again the data output during this I/O cycle is the data from conversion N.

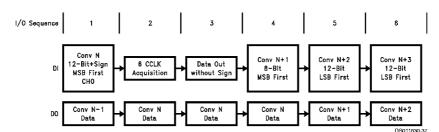


FIGURE 8. Changing the ADC's Conversion Configuration

The number of SCLKs applied to the A/D during any conversion I/O sequence should vary in accord with the data out word format chosen during the previous conversion I/O sequence. The various formats and resolutions available are shown in *Table 1*. In *Figure 8*, since 8-bit without sign MSB first format was chosen during I/O sequence 4, the number of SCLKs required during I/O sequence 5 is 8. In the following I/O sequence the format changes to 12-bit without sine MSB first; therefore the number of SCLKs required during I/O sequence 6 changes accordingly to 12.

### 1.3 CS Low Continuously Considerations

When  $\overline{\text{CS}}$  is continuously low, it is important to transmit the exact number of SCLK pulses that the ADC expects. Not doing so will desynchronize the serial communications to the ADC. When the supply power is first applied to the ADC, it will expect to see 13 SCLK pulses for each I/O transmission. The number of SCLK pulses that the ADC expects to see is the same as the digital output word length. The digital output word length is controlled by the Data Out (DO) format. The DO format maybe changed any time a conversion is started or when the sign bit is turned on or off. The table below details out the number of clock periods required for different DO formats:

DO Format		Number of SCLKs
		Expected
8-Bit MSB or LSB First	SIGN OFF	8
	SIGN ON	9
12-Bit MSB or LSB First	SIGN OFF	12
	SIGN ON	13
16-Bit MSB or LSB first	SIGN OFF	16
	SIGN ON	17

If erroneous SCLK pulses desynchronize the communications, the simplest way to recover is by cycling the power supply to the device. Not being able to easily resynchronize the device is a shortcoming of leaving  $\overline{\text{CS}}$  low continuously.

The number of clock pulses required for an I/O exchange may be different for the case when  $\overline{\text{CS}}$  is left low continuously vs. the case when  $\overline{\text{CS}}$  is cycled. Take the I/O sequence

detailed in Figure 7 (Typical Power Supply Sequence) as an example. The table below lists the number of SCLK pulses required for each instruction:

Instruction	CS Low	CS Strobed		
	Continuously			
Auto Cal	13 SCLKs	8 SCLKs		
Read Status	13 SCLKs	8 SCLKs		
Read Status	13 SCLKs	8 SCLKs		
12-Bit + Sign Conv 1	13 SCLKs	8 SCLKs		
12-Bit + Sign Conv 2	13 SCLKs	13 SCLKs		

### 1.4 Analog Input Channel Selection

The data input on DI also selects the channel configuration for a particular A/D conversion (See *Tables 2, 3, 4, 5*). In *Figure 8* the only times when the channel configuration could be modified would be during I/O sequences 1, 4, 5 and 6. Input channels are reselected before the start of each new conversion. Shown below is the data bit stream required on DI, during I/O sequence number 4 in *Figure 8*, to set CH1 as the positive input and CH0 as the negative input for the different versions of ADCs:

Part DI Data									
Number	DIO	DI1	DI2	DI3	DI4	DI5	DI6	DI7	
ADC12L030	L	Η	L	L	Ι	L	Х	Х	
ADC12L032	L	Ι	L	L	Н	L	Х	Х	
ADC12L034	L	Н	L	L	L	Н	L	Х	
ADC12L038	L	Ι	L	L	L	L	Н	L	

Where X can be a logic high (H) or low (L).

### 1.5 Power Up/Down

The ADC may be powered down at any time by taking the PD pin HIGH or by the instruction input on DI (see *Tables 5*, 6, and the Power Up/Down timing diagrams). When the ADC is powered down in this way the circuitry necessary for an A/D conversion is deactivated. The circuitry necessary for digital I/O is kept active. Hardware power up/down is controlled by the state of the PD pin. Software power up/down is controlled by the instruction issued to the ADC. If a software power up instruction is issued to the ADC while a hardware power down is in effect (PD pin high) the device will remain

in the power-down state. If a software power down instruction is issued to the ADC while a hardware power up is in effect (PD pin low), the device will power down. When the device is powered down by software, it may be powered up by either issuing a software power up instruction or by taking PD pin high and then low. If the power down command is issued during an A/D conversion, that conversion is disrupted. Therefore, the data output after power up cannot be relied on

### 1.6 User Mode and Test Mode

An instruction may be issued to the ADC to put it into test mode. Test mode is used by the manufacturer to verify complete functionality of the device. During test mode CH0-CH7 become active outputs. If the device is inadvertently put into the test mode with  $\overline{\text{CS}}$  low continuously, the serial communications may be desynchronized. Synchronization may be regained by cycling the power supply voltage to the device. Cycling the power supply voltage will also set the device into user mode. If  $\overline{\text{CS}}$  is used in the serial interface, the ADC may be queried to see what mode it is in. This is done by issuing a "read STATUS register" instruction to the ADC. When bit 9 of the status register is high the ADC is in test mode; when bit 9 is low the ADC is in user mode. As an alternative to cycling the power supply, an instruction sequence may be used to return the device to user mode. This instruction sequence must be issued to the ADC using  $\overline{CS}$ .

The following table lists the instructions required to return the device to user mode:

Instruction				DI I	Data			
insu ucuon	DIO	DI1	DI2	DI3	DI4	DI5	DI6	DI7
TEST MODE	Н	Х	Х	Х	Н	Н	Н	Н
RESET	L	L	L	L	Н	Н	Н	L
TEST MODE	L	L	L	L	Н	L	Н	L
INSTRUCTIONS	L	L	L	L	Н	L	Н	Н
USER MODE	L	L	L	L	Н	Н	Н	Н
Power Up	L	L	L	L	Н	L	Н	L
Set DO with	Н							
or without	or	L	L	L	Н	Н	L	Н
Sign	L							
Set	Н	Н						
Acquisition	or	or	L	L	Н	Н	н	L
Time	L	L						
Start	Н	Н	Н	Н		Н	Н	Η
a	or	or	or	or	L	or	or	or
Conversion	L	L	L	L		L	L	L

X = Don't Care

After returning to user mode with the user mode instruction the power up, data with or without sign, and acquisition time instructions need to be resent to ensure that the ADC is in the required state before a conversion is started.

### 1.7 Reading the Data Without Starting a Conversion

The data from a particular conversion may be accessed without starting a new conversion by ensuring that the  $\overline{\text{CONV}}$  line is taken high during the I/O sequence. See the Read Data timing diagrams. Table 6 describes the operation of the  $\overline{\text{CONV}}$  pin.

### 2.0 DESCRIPTION OF THE ANALOG MULTIPLEXER

For the ADC12L038, the analog input multiplexer can be configured with 4 differential channels or 8 single ended channels with the COM input as the zero reference or any combination thereof (see Figure 9). The difference between the voltages on the  $V_{\rm REF}^+$  and  $V_{\rm REF}^-$  pins determines the input voltage span ( $V_{\rm REF}$ ). The analog input voltage range is 0 to  $V_{\rm A}^+$ . Negative digital output codes result when  $V_{\rm IN}^- > V_{\rm IN}^+$ . The actual voltage at  $V_{\rm IN}^-$  or  $V_{\rm IN}^+$  cannot go below AGND

## +(-) CH2 -(+) CH3 +(-) CH4 -(+) CH3 +(-) CH4 -(+) CH5 -(+) CH6 -(+) CH6

8 Single-Ended Channels with COM as Zero Reference

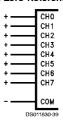


FIGURE 9.

CH0, CH2, CH4, and CH6 can be assigned to the MUX-OUT1 pin in the differential configuration, while CH1, CH3, CH5, and CH7 can be assigned to the MUXOUT2 pin. In the differential configuration, the analog inputs are paired as follows: CH0 with CH1, CH2 with CH3, CH4 with CH5 and CH6 with CH7. The A/DIN1 and A/DIN2 pins can be assigned positive or negative polarity.

With the single-ended multiplexer configuration CH0 through CH7 can be assigned to the MUXOUT1 pin. The COM pin is always assigned to the MUXOUT2 pin. A/DIN1 is assigned as the positive input; A/DIN2 is assigned as the negative input. (See Figure 10).

The Multiplexer assignment tables for the ADC12L030,2,4,8 (*Tables 2, 3, 4*) summarize the aforementioned functions for the different versions of A/Ds.

### **Application Hints** (Continued) Differential Single-Ended Configuration Configuration CH4 MUX OUT 1 CH<sub>2</sub> CH3 CH<sub>6</sub> MUX OUT 1 CH5 CH3 CH6 MUX OUT 2 COM DS011830-40 A/DIN1 and A/DIN2 can be assigned as the + or - input A/DIN1 is + input A/DIN2 is - input FIGURE 10. ٧, + ANALOG 10 μF СНО INPUT VOLTAGE O +3.3V CH<sub>2</sub> RANGE ASSIGNED 0V TO 2.5V (+) INPUT $V_D +$ 12 BITS UNSIGNED 1k ADC12L03Y ASSIGNED (-) INPUT сом $V_{REF}$ O +2.5V 10 μF V<sub>REF</sub> LM4040AIM3-2.5 DGND AGND ANALOG

FIGURE 11. Single-Ended Biasing

### 2.1 Biasing for Various Multiplexer Configurations

VOLTAGE GROUND REFERENCE

Figure 11 is an example of biasing the device for single-ended operation. The sign bit is always low. The digital output range is 0 0000 0000 0000 to 0 1111 1111 1111. One LSB is equal to 610  $\mu$ V (2.5V/4096 LSBs).

For pseudo-differential signed operation the biasing circuit shown in Figure 12 shows a signal AC coupled to the ADC. This gives a digital output range of –4096 to +4095. With a 1.25V reference, as shown, 1 LSB is equal to 305  $\mu$ V. Although the ADC is not production tested with a 1.25V reference linearity error typically will not change more than 0.3 LSB. With the ADC set to an acquisition time of 10 clock periods the input biasing resistor needs to be  $600\Omega$  or less. Notice though that the input coupling capacitor needs to be

made fairly large to bring down the high pass corner. Increasing the acquisition time to 34 clock periods (with a 5 MHz CCLK frequency) would allow the  $600\Omega$  to increase to 6k, which with a 1  $\mu\text{F}$  coupling capacitor would set the high pass corner at 26 Hz. The value of R1 will depend on the value of R2.

DS011830-46

An alternative method for biasing pseudo-differential operation is to use the +1.25V from the LM4040 to bias any amplifier circuits driving the ADC as shown in *Figure 13*. The value of the resistor pull-up biasing the LM4040-2.5 will depend upon the current required by the op amp biasing circuitry. Fully differential operation is shown in *Figure 14*. One LSB for this case is equal to (2.5V/4096) = 610 mV.

### Application Hints (Continued) ANALOG INPUT VOLTAGE 10 μF 0.01 μF 0.1 μF СНО CH1 **O** +3.3V RANGE OV TO 2.5V CH2 ASSIGNED (+) INPUT ٧<sub>D</sub> 12 BITS SIGNED 600Ω (DEPENDS ON ADC12L03Y ASSIGNED ACQUISITION V<sub>REF</sub> COM O +1.25V 0.1 μF 10 μF V<sub>REF</sub>-LM4041AIM3-1.25 DGND AGND ANALOG VOLTAGE > GROUND REFERENCE FIGURE 12. Pseudo-Differential Biasing with the Signal Source AC Coupled Directly into the ADC

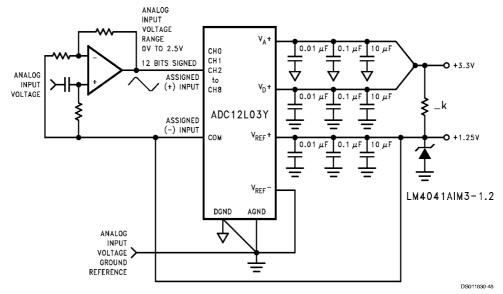


FIGURE 13. Alternative Pseudo-Differential Biasing

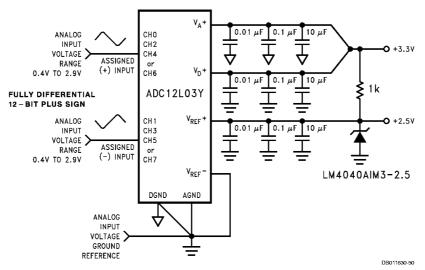


FIGURE 14. Fully Differential Biasing

### 3.0 REFERENCE VOLTAGE

The difference in the voltages applied to the  $V_{REF}^+$  and  $V_{REF}^-$  defines the analog input span (the difference between the voltage applied between two multiplexer inputs or the voltage applied to one of the multiplexer inputs and analog ground), over which 4095 positive and 4096 negative codes exist. The voltage sources driving  $V_{REF}^-$  or  $V_{REF}^-$  must have very low output impedance and noise.

The ADC12L030/2/4/8 can be used in either ratiometric or absolute reference applications. In ratiometric systems, the analog input voltage is proportional to the voltage used for the ADC's reference voltage. When this voltage is the system power supply, the  $V_{\text{REF}}^{\,+}$  pin is connected to  $V_{\text{A}}^{\,+}$  and  $V_{\text{REF}}^{\,-}$  is connected to ground. This technique relaxes the system reference stability requirements because the analog input voltage and the ADC reference voltage move together. This maintains the same output code for given input conditions. For absolute accuracy, where the analog input voltage varies between very specific voltage limits, a time and temperature stable voltage source can be connected to the reference inputs. Typically, the reference voltage's magnitude will require an initial adjustment to null reference voltage induced full-scale errors.

Below are recommended references along with some key specifications.

•				
	Output	Temperature		
Part Number	Voltage	Coefficient		
	Tolerance	(max)		
LM4041CIM3-Adj	±0.5%	±100ppm/°C		

The reference voltage inputs are not fully differential. The ADC12L030/2/4/8 will not generate correct conversions or comparisons if  $V_{\rm REF}^+$  is taken below  $V_{\rm REF}^-$ . Correct conversions result when  $V_{\rm REF}^+$  and  $V_{\rm REF}^-$  differ by 1V and remain, at all times, between ground and  $V_{\rm A}^+$ . The  $V_{\rm REF}$  common mode range,  $(V_{\rm REF}^+$  +  $V_{\rm REF}^-)/2$ , is restricted to (0.1 x  $V_{\rm A}^+$ ) to (0.6 x  $V_{\rm A}^+$ ). Therefore, with  $V_{\rm A}^+=3.3$ V the center of the ref-

erence ladder should not go below 0.33V or above 1.98V. Figure 15 is a graphic representation of the voltage restrictions on  $V_{\text{REF}}^+$  and  $V_{\text{REF}}^-$ .

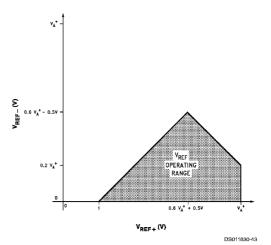


FIGURE 15. V<sub>REF</sub> Operating Range

### 4.0 ANALOG INPUT VOLTAGE RANGE

The ADC12L030/2/4/8's fully differential ADC generate a two's complement output that is found by using the equations shown below:

for (12-bit) resolution the Output Code =

$$\frac{(V_{IN}^+ - V_{IN}^-) (4096)}{(V_{BFE}^+ - V_{BFE}^-)}$$

for (8-bit) resolution the Output Code =

$$\frac{({\rm V_{IN}}^+ - {\rm V_{IN}}^-)~(256)}{({\rm V_{REF}}^+ - {\rm V_{REF}}^-)}$$

Round off to the nearest integer value between –4096 to 4095 for 12-bit resolution and between –256 to 255 for 8-bit resolution if the result of the above equation is not a whole number

Examples are shown in the table below:

V <sub>REF</sub> *	V <sub>REF</sub> -	V <sub>IN</sub> +	V <sub>IN</sub> -	Digital Output Code
+2.5V	+1V	+1.5V	ov	0,1111,1111,1111
+2.500V	ov	+2V	ov	0,1100,1100,1101
+2.500V	ov	+2.499 <b>V</b>	+2.500V	1,1111,1111,1111
+2.500V	ov	٥V	+2.500V	1,0000,0000,0000

### 5.0 INPUT CURRENT

At the start of the acquisition window  $(t_A)$  a charging current flows into or out of the analog input pins (A/DIN1 and A/DIN2) depending on the input voltage polarity. The analog input pins are CH0–CH7 and COM when A/DIN1 is tied to MUXOUT1 and A/DIN2 is tied to MUXOUT2. The peak value of this input current will depend on the actual input voltage applied, the source impedance and the internal multiplexer switch on resistance. With MUXOUT1 tied to A/DIN1 and MUXOUT2 tied to A/DIN2 the internal multiplexer switch on resistance is typically 1.6 k $\Omega$ . The A/DIN1 and A/DIN2 mux on resistance is typically 750 $\Omega$ .

### 6.0 INPUT SOURCE RESISTANCE

For low impedance voltage sources ( $<600\Omega$ ), the input charging current will decay, before the end of the S/H's acquisition time of 2 µs (10 CCLK periods with f<sub>C</sub> = 5 MHz), to a value that will not introduce any conversion errors. For high source impedances, the S/H's acquisition time can be increased to 18 or 34 CCLK periods. For less ADC resolution and/or slower CCLK frequencies the S/H's acquisition time may be decreased to 6 CCLK periods. To determine the number of clock periods (N<sub>C</sub>) required for the acquisition time with a specific source impedance for the various resolutions the following equations can be used:

12 Bit + Sign 
$$N_C = [R_S + 2.3] \times f_C \times 0.824$$
  
8 Bit + Sign  $N_C = [R_S + 2.3] \times f_C \times 0.57$ 

Where  $f_C$  is the conversion clock (CCLK) frequency in MHz and  $R_S$  is the external source resistance in  $k\Omega$ . As an example, operating with a resolution of 12 Bits-sign, a 5 MHz clock frequency and maximum acquistion time of 34 conversion clock periods the ADC's analog inputs can handle a source impedance as high as 6  $k\Omega$ . The acquisition time may

also be extended to compensate for the settling or response time of external circuitry connected between the MUXOUT and A/DIN pins.

The acquisition time  $(t_A)$  is started by a falling edge of SCLK and ended by a rising edge of CCLK (see Timing Diagrams). If SCLK and CCLK are asynchronous one extra CCLK clock period may be inserted into the programmed acquisition time for synchronization. Therefore with asnychronous SCLK and CCLK the acquisition time will change from conversion to conversion.

### 7.0 INPUT BYPASS CAPACITANCE

External capacitors (0.01  $\mu$ F–0.1  $\mu$ F) can be connected between the analog input pins, CH0–CH7, and analog ground to filter any noise caused by inductive pickup associated with long input leads. These capacitors will not degrade the conversion accuracy.

### 8.0 NOISE

The leads to each of the analog multiplexer input pins should be kept as short as possible. This will minimize input noise and clock frequency coupling that can cause conversion errors. Input filtering can be used to reduce the effects of the noise sources.

### 9.0 POWER SUPPLIES

Noise spikes on the  $V_A^+$  and  $V_D^+$  supply lines can cause conversion errors; the comparator will respond to the noise. The ADC is especially sensitive to any power supply spikes that occur during the auto-zero or linearity correction. The minimum power supply bypassing capacitors recommended are low inductance tantalum capacitors of 10  $\mu F$  or greater paralleled with 0.1  $\mu F$  monolithic ceramic capacitors. More or different bypassing may be necessary depending on the overall system requirements. Separate bypass capacitors should be used for the  $V_A^+$  and  $V_D^+$  supplies and placed as close as possible to these pins.

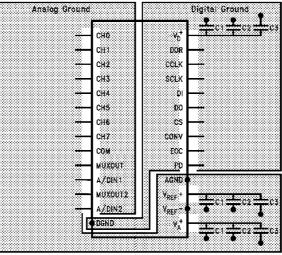
### 10.0 GROUNDING

The ADC12L030/2/4/8's performance can be maximized through proper grounding techniques. These include the use of separate analog and digital ground planes. The digital ground plane is placed under all components that handle digital signals, while the analog ground plane is placed under all components that handle analog ground planes are connected together at only one point, either the power supply ground or at the pins of the ADC. This greatly reduces the occurence of ground loops and noise.

Shown in Figure 16 is the ideal ground plane layout for the ADC12L038 along with ideal placement of the bypass capacitors. The circuit board layout shown in Figure 16 uses three bypass capacitors: 0.01  $\mu F$  (C1) and 0.1  $\mu F$  (C2) surface mount capacitors and 10  $\mu F$  (C3) tantalum capacitor.

### 11.0 CLOCK SIGNAL LINE ISOLATION

The ADC12L030/2/4/8's performance is optimized by routing the analog input/output and reference signal conductors as far as possible from the conductors that carry the clock signals to the CCLK and SCLK pins. Ground traces parallel to the clock signal traces can be used on printed circuit boards to reduce clock signal interference on the analog input/output pins.



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FIGURE 16. Ideal Ground Plane for the ADC12L038

### 12.0 THE CALIBRATION CYCLE

A calibration cycle needs to be started after the power supplies, reference, and clock have been given enough time to stabilize after initial turn on. During the calibration cycle, correction values are determined for the offset voltage of the sampled data comparator and any linearity and gain errors. These values are stored in internal RAM and used during an analog-to-digital conversion to bring the overall full-scale, offset, and linearity errors down to the specified limits. Full-scale error typically changes ±0.4 LSB over temperature and linearity error changes even less; therefore it should be necessary to go through the calibration cycle only once after power up if the Power Supply Voltage and the ambient temperature do not change significantly (see the curves in the Typical Performance Characteristics).

### 13.0 THE AUTO-ZERO CYCLE

To correct for any change in the zero (offset) error of the A/D, the auto-zero cycle can be used. It may be necessary to do an auto-zero cycle whenever the ambient temperature or the power supply voltage change significantly. (See the curves titled "Zero Error Change vs Ambient Temperature" and "Zero Error Change vs Supply Voltage" in the Typical Performance Characteristics.)

### 14.0 DYNAMIC PERFORMANCE

Many applications require the A/D converter to digitize AC signals, but the standard DC integral and differential nonlinearity specifications will not accurately predict the A/D converter's performance with AC input signals. The important specifications for AC applications reflect the converter's ability to digitize AC signals without significant spectral errors and without adding noise to the digitized signal. Dynamic characteristics such as signal-to-noise (S/N), signal-to-noise + distortion ratio (S/(N + D)), effective bits, full power bandwidth, aperture time and aperture jitter are quantitative measures of the A/D converter's capability.

An A/D converter's AC performance can be measured using Fast Fourier Transform (FFT) methods. A sinusoidal waveform is applied to the A/D converter's input, and the transform is then performed on the digitized waveform. S/(N + D) and S/N are calculated from the resulting FFT data, and a spectral plot may also be obtained.

The A/D converter's noise and distortion levels will change with the frequency of the input signal, with more distortion and noise occurring at higher signal frequencies. This can be seen in the S/(N+D) versus frequency curves. These curves will also give an indication of the full power bandwidth (the frequency at which the S/(N+D) or S/N drops 3 dB).

Effective number of bits can also be useful in describing the A/D's noise performance. An ideal A/D converter will have some amount of quantization noise, determined by its resolution, which will yield an optimum S/N ratio given by the following equation:

$$S/N = (6.02 \times n + 1.76) dB$$

where n is the A/D's resolution in bits.

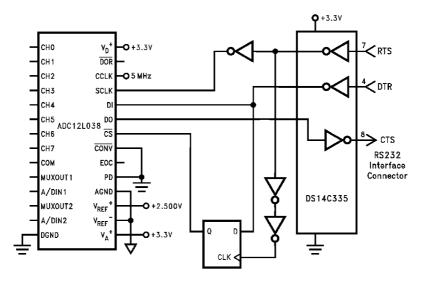
The effective bits of a real A/D converter, therefore, can be found by:

$$n(effective) = \frac{S/N(dB) - 1.76}{6.02}$$

As an example, this device with a  $\pm 2.5V$ , 10 kHz sine wave input signal will typically have a S/N of 78 dB, which is equivalent to 12.6 effective bits.

### 15.0 AN RS232 SERIAL INTERFACE

Shown below is a schematic for an RS232 interface to any IBM and compatible PCs. The DTR, RTS, and CTS RS232 signal lines are buffered via level translators and connected to the ADC12L038's DI, SCLK, and DO pins, respectively. The D flip flop drive the  $\overline{\text{CS}}$  control line.



Note:  $V_A^+$ ,  $V_D^+$ , and  $V_{REF}^+$  on the ADC12L038 each have 0.01  $\mu F$  and 0.1  $\mu F$  chip caps, and 10  $\mu F$  tantalum caps. All logic devices are bypassed with 0.1  $\mu F$  caps. The DS14C335 has an internal DC-DC converter that generates the necessary TlA/EIA-232-E output levels from a 3.3V supply. There are four 0.47  $\mu F$  capacitors required for the DC-DC converter that are not shown in the above schematic.

The assignment of the RS232 port is shown below

					B5	B4	В3	B2	B1	B0
COM1	Input Address	3FE	Χ	Х	Х	CTS	Χ	Х	Х	Х
	Output Address	3FC	Х	Х	Х	0	Х	Х	RTS	DTR

A sample program, written in Microsoft™ QuickBasic, is shown on the next page. The program prompts for data mode select instruction to be sent to the A/D. This can be found from the Mode Programming table shown earlier. The data should be entered in "1"s and "0"s as shown in the table with DI0 first. Next the program prompts for the number of SCLKs required for the programmed mode select instruction. For instance, to send all "0"s to the A/D, selects CH0 as the +input, CH1 as the -input, 12-bit conversion, and 13-bit MSB first data output format (if the sign bit was not turned off by a previous instruction). This would require 13 SCLK periods since the output data format is 13 bits. The part powers up with No Auto Cal, No Auto Zero, 10 CCLK Acquisition Time, 12-bit conversion, data out with sign, 12- or 13-bit MSB First, power up, and user mode. Auto Cal, Auto Zero, Power UP and Power Down instructions do not change these default settings. The following power up sequence should be followed:

- 1. Run the program
- Prior to responding to the prompt apply the power to the ADC12L038
- 3. Respond to the program prompts

It is recommended that the first instruction issued to the ADC12L038 be Auto Cal (see Section 1.1).

### Application Hints (Continued) 'variables DOL=Data Out word length, DI=Data string for A/D DI input, DO=A/D result string 'SET CS# HIGH OUT &H3FC, (&H2 OR INP (&H3FC)) 'set RTS HIGH OUT &H3FC, (&HFE AND INP (&H3FC)) OUT &H3FC, (&HFD AND INP (&H3FC)) 'SET DTR LOW OUT &H3FC, (&HEF AND INP (&H3FC)) 'set B4 low 10 LINE INPUT "DI data for ADC12038 (see Mode Table on data sheet)"; DI\$ INPUT "ADC12038 output word length (8,9,12,13,16 or 17)"; DOL 'SET CS# HIGH OUT &H3FC, (&H2 OR INP (&H3FC)) 'set RTS HIGH OUT &H3FC, (&HFE AND INP (&H3FC)) OUT &H3FC, (&HFD AND INP (&H3FC)) 'SET DTR LOW 'SET RTS LOW 'SET CS# LOW OUT &H3FC, (&H2 OR INP (&H3FC)) OUT &H3FC, (&H1 OR INP (&H3FC)) 'set RTS HIGH 'SET DTR HIGH OUT &H3FC, (&HFD AND INP (&H3FC)) 'SET RTS LOW DOS-"" 'reset DO variable OUT &H3FC, (&H1 OR INP (&H3FC)) 'SET DTR HIGH OUT &H3FC, (&HFD AND INP (&H3FC)) 'SCLK low FOR N=1 TO 8 Temp\$=MID\$(DI\$,N,1) IF Temp\$="O"THEN OUT &H3FC, (&H1 OR INP(&H3FC)) ELSE OUT &H3FC, (&HFE AND INP (&H3FC)) END IF 'out DI OUT &H3FC,(&H2 OR INP (&H3FC)) 'SCLK high IF (INP (&H3FE) AND 16)=16 THEN DO\$=DO\$+\*O\* ELSE DO\$=DO\$+"1" 'Input DO END IF OUT &H3FC, (&H1 OR INP (&H3FC)) OUT &H3FC, (&HFD AND INP (&H3FC)) 'SET DTR HIGH 'SCLK low NEXT N IF DOL>8 THEN FOR N=9 TO DOL OUT &H3FC, (&H1 OR INP (&H3FC)) 'SET DTR HIGH OUT &H3FC,(&HFD AND INP (&H3FC)) 'SCLK low 'SCLK high OUT &H3FC,(&H2 OR INP (&H3FC))

IF (INP(&H3FE) AND &H16)=&H16 THEN

INPUT "Enter "C" to convert else "RETURN" to alter DI data"; s\$

OUT &H3FC,(&HFA AND INP(&H3FC))

IF s\$="C" OR s\$="c" THEN

DO\$=DO\$+"0"

DO\$=DO\$+"1"
END IF
NEXT N
END IF

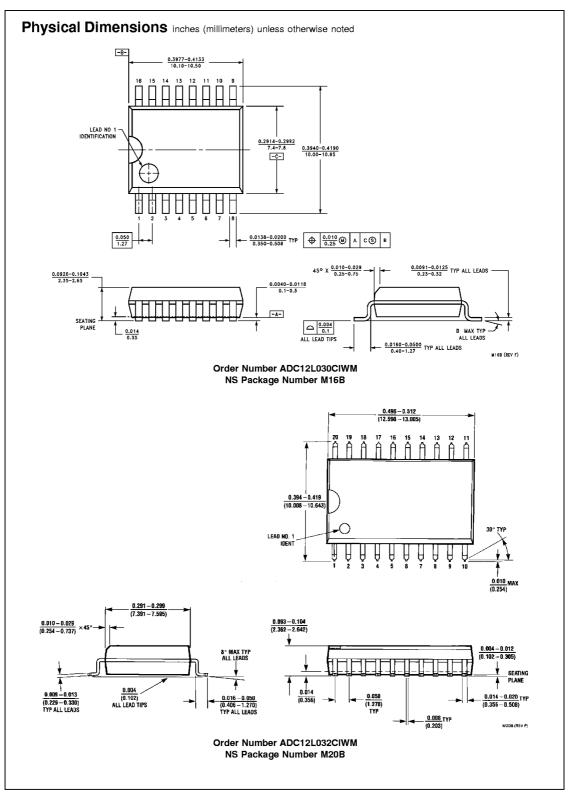
FOR N=1 TO 500 NEXT N PRINT DO\$

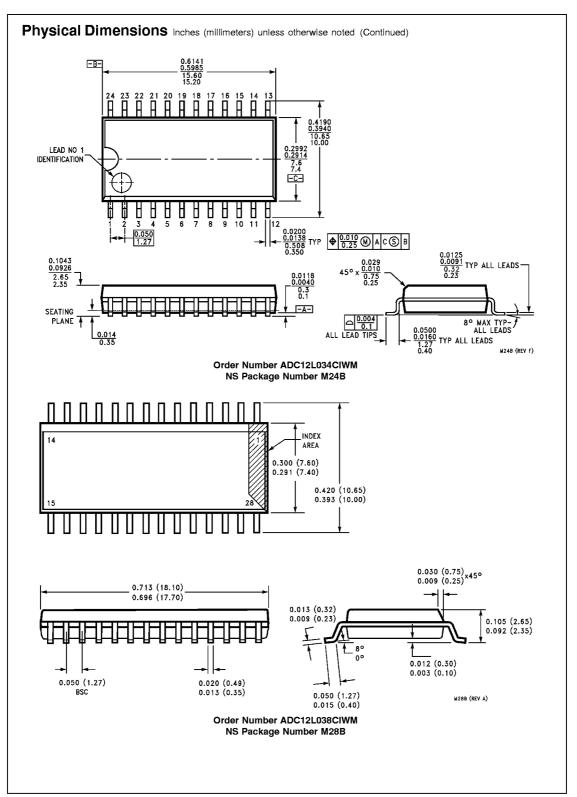
GOTO 20 ELSE GOTO 10 END IF END

ELSE

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'SCLK low and DI high





### **Notes**

### LIFE SUPPORT POLICY

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